



Ref. Certif. No.

DE 3 - 30464

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

SYSTEME CEI D'ACCEPTATION MUTUELLE DE CERTIFICATS D'ESSAIS DES EQUIPEMENTS ELECTRIQUES (IECEE) METHODE OC

**CB TEST CERTIFICATE
CERTIFICAT D'ESSAI OC**

Product

Laboratory equipment
(microscope system)

Name and address of the applicant

Leica Microsystems CMS GmbH
Ernst-Leitz-Straße 17-37
35578 Wetzlar, GERMANY

Name and address of the manufacturer

Leica Microsystems CMS GmbH
Ernst-Leitz-Straße 17-37, 35578 Wetzlar, GERMANY

Name and address of the factory

Leica Microsystems CMS GmbH
Ernst-Leitz-Straße 17-37, 35578 Wetzlar, GERMANY

Ratings and principal characteristics

WSU

Rated voltage: 100-240 V

Rated frequency: 50/60 Hz

Rated power: 250 VA

Protection class: I

Supply Unit Scanhead (supplied Infinity Scanner)

Rated voltage: 100-240 V

Rated frequency: 50/60 Hz

Rated power: 150 VA

Protection class: I

Pulsed Laser Unit 355 nm (Ablation laser)

Rated voltage : 12 VDC (supplied via external
limited power supply unit)

Protection class: III

Laser class: 1

Protection class: I

Leica

Trade mark (if any)

Customer's Testing Facility (CTF) Stage used

CTF Stage 1

Model/type Ref.

The microscope system consists of:
WSU, Pulsed Laser Unit 355 nm,
Infinity scanner, Supply Unit Scanhead

Additional information (if necessary)

A sample of the product was tested and found
to be in conformity with

IEC 61010-1:2010

IEC 60825-1:2014

as shown in the Test Report Ref. No.

028-713099377-000

which forms part of this certificate

This CB Test Certificate is issued by the National Certification Body
Ce Certificat d'essai OC est établi par l'Organisme **National de Certification**

Date,

2017-06-01

CB 17 05 56257 160

Ralph Fischer



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Product Service